

Search Notes

Application/Control No.

09/621,476

Examiner

Minh Dieu Nguyen

Applicant(s)/Patent under
Reexamination

KAHN ET AL.

Art Unit

2137

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 380 | 239-240 | 6/28/2005 | MDN |
| 705 | 51-52 | 6/28/2005 | MDN |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--|-----------|------|
| Updated inventor name search on EAST (US-PAT; US-PGPUB; EPO; JPO; DERWENT; IBM-TDB) | 6/28/2005 | MDN |
| Updated test and class search on EAST (US-PAT; US-PGPUB; EPO; JPO; DERWENT; IBM-TDB) | 6/28/2005 | MDN |
| Consulted with M. Smithers on double patenting issue | 6/28/2005 | MDN |
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